

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:

Atty Dkt. 4074-7

C# M#

AOKI et al

TC/A.U.

1756

Serial No. 10/689,666

OCT 11 2005

Examiner: Rosasco, Stephen D.

Filed: October 22, 2003

Date: October 11, 2005

Title: PHOTOMASK DEFECT TESTING METHOD, PHOTOMASK MANUFACTURING METHOD AND SEMICONDUCTOR INTEGRATED CIRCUIT MANUFACTURING METHOD

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**RESPONSE/AMENDMENT/LETTER**

This is a response/amendment/letter in the above-identified application and includes an attachment which is hereby incorporated by reference and the signature below serves as the signature to the attachment in the absence of any other signature thereon.

☐ **Correspondence Address Indication Form Attached.**

**Fees are attached as calculated below:**

Total effective claims after amendment	9	minus highest number	
previously paid for	20	(at least 20) =	0 x \$50.00
			\$0.00 (1202)/\$0.00 (2202) \$

Independent claims after amendment	6	minus highest number	
previously paid for	6	(at least 3) =	0 x \$200.00
			\$0.00 (1201)/\$0.00 (2201) \$

If proper multiple dependent claims now added for first time, (ignore improper); add  
\$360.00 (1051)/\$180.00 (2051) \$

Petition is hereby made to extend the current due date so as to cover the filing date of this  
paper and attachment(s)

One Month Extension	\$120.00 (1251)/\$60.00 (2251)	
Two Month Extensions	\$450.00 (1252)/\$225.00 (2252)	
Three Month Extensions	\$1020.00 (1253)/\$510.00 (2253)	
Four Month Extensions	\$1590.00 (1254)/\$795.00 (2254)	\$ 120.00

Terminal disclaimer enclosed, add  
\$130.00 (1814)/ \$65.00 (2814) \$

☐ Applicant claims "small entity" status. ☐ Statement filed herewith

Rule 56 Information Disclosure Statement Filing Fee  
\$180.00 (1806) \$

Assignment Recording Fee  
\$40.00 (8021) \$

Other:  
\$

**TOTAL FEE ENCLOSED \$ 120.00**

The Commissioner is hereby authorized to charge any deficiency, or credit any overpayment, in the fee(s) filed, or asserted to be filed, or which should have been filed herewith (or with any paper hereafter filed in this application by this firm) to our Account No. 14-1140. A duplicate copy of this sheet is attached.

901 North Glebe Road, 11th Floor  
Arlington, Virginia 22203-1808  
Telephone: (703) 816-4000  
Facsimile: (703) 816-4100  
JAR:caj

NIXON & VANDERHYE P.C.  
By Atty: Joseph A. Rhoads, Reg. No. 37,515

Signature: \_\_\_\_\_



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

AOKI et al

Atty. Ref.: 4074-7; Confirmation No. 6492

Appl. No. 10/689,666

TC/A.U. 1756

Filed: October 22, 2003

Examiner: Rosasco, Stephen D.

For: PHOTOMASK DEFECT TESTING METHOD, PHOTOMASK MANUFACTURING  
METHOD AND SEMICONDUCTOR INTEGRATED CIRCUIT MANUFACTURING  
METHOD

\* \* \* \* \*

October 11, 2005

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**RESPONSE TO OFFICE ACTION**

Responsive to the Official Action dated June 8, 2005 (for which petition is hereby made  
for a one month extension of time), reconsideration is respectfully requested for at least the  
following reasons:

10/12/2005 JADD01 00000147 10689666

01 FC:1251

120.00 OP